



## Metrology Report PSI

Date: 8. August 2013  
People: Uwe Flechsig  
Sibylle Spielmann-Jäggi  
Address: Paul Scherrer Institut  
CH-5232 Villigen PSI

### Type of Measurement

<i>Type of measurement</i>	<i>Device</i>	<i>Resolution</i>	<i>Spatial sampling area</i>
Long Trace Profiler onedimensional, absolute slope measuring device	Ocean Optics LTP V	$\leq 0.5 \mu\text{rad}$	$1 \text{ m} \leq \lambda \leq 1500 \text{ mm}$

## Specification Plane Mirror M1\_1, M1\_4

---

**Blank material** Si.

**Blank dimensions** length: 115 mm, width: 40/30 mm, height: 20 mm

**Optical surface** length: 100 mm, width: 4 mm

**Shape** flat

## Results M1\_1

---

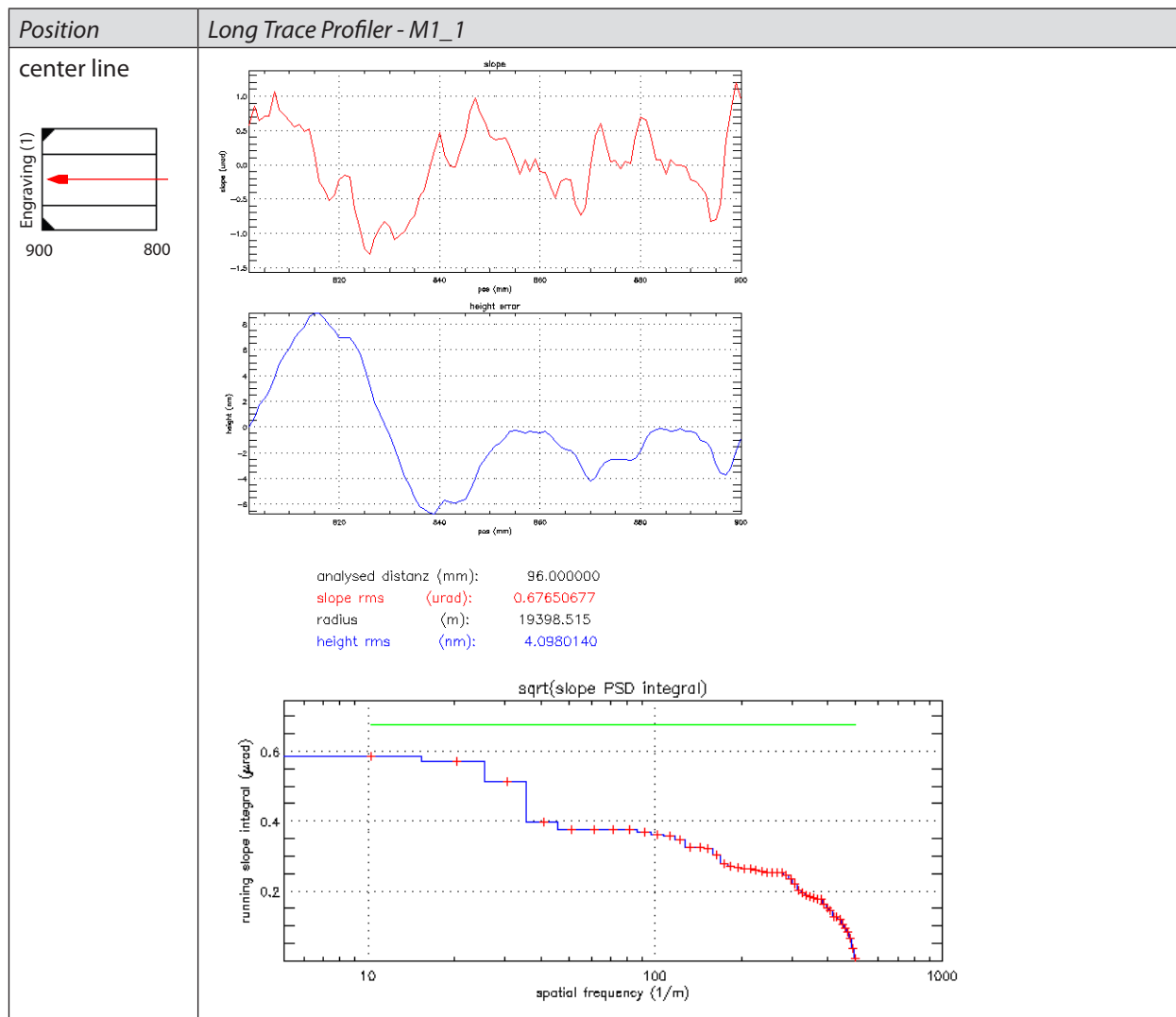
- Radius = 19.39 km (concave)
- Slope error = 0.67  $\mu$ rad rms
- Roughness = 0.276 nm rms

## Results M1\_4

---

- Radius = 27.48 km (concave)
- Slope error = 0.61  $\mu$ rad rms
- Roughness = 0.41 nm rms

## Measurments M1\_1



## Measurments M1\_4

